

Automotive

Samsung eMMC Product family

eMMC 5.1 Specification compatibility

Datasheet

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INTRODUCTION

SAMSUNG eMMC is an embedded MMC solution designed in a BGA package form. eMMC operation is identical to a MMC device and therefore is a simple read and write to memory using MMC protocol v5.1 which is a industry standard.

eMMC consists of NAND flash and a MMC controller. 3V supply voltage is required for the NAND area (V_{DDF} or V_{CC}) whereas 1.8V or 3V dual supply voltage (V_{DD} or V_{CCQ}) is supported for the MMC controller. SAMSUNG eMMC supports HS400 in order to improve sequential bandwidth, especially sequential read performance.

There are several advantages of using eMMC. It is easy to use as the MMC interface allows easy integration with any microprocessor with MMC host. Any revision or amendment of NAND is invisible to the host as the Embedded MMC controller insulates NAND technology from the host. This leads to faster product development as well as faster times to market.

The embedded flash management software or FTL(Flash Transition Layer) of eMMC manages Wear Leveling, Bad Block Management and ECC. The FTL supports all features of the Samsung NAND flash and achieves optimal performance.

1.0 PRODUCT LIST

[Table 1] Product List

| Capacities | eMMC Part ID | NAND Flash Type | User Density(%) | Power System | Package size | Pin Configuration |
|------------|-----------------|-----------------|-----------------|----------------------------------------------------------------------------------------------------------------------|--------------------------|-------------------|
| 8GB | KLM8G1GEUF-B04P | 64 Gb MLC x1 | 91.0% | - Interface power: V_{DD} (1.70 V ~ 1.95 V or 2.7 V ~ 3.6 V) - Memory power: V_{DDF} (2.7 V ~ 3.6 V) | 11.5 mm x 13 mm x 0.8 mm | 153 FBGA |
| | KLM8G1GEUF-B04Q | | | | | |
| 16GB | KLMAG2GEUF-B04P | 64 Gb MLC x2 | | | | |
| | KLMAG2GEUF-B04Q | | | | | |
| 32GB | KLMBG4GEUF-B04P | 64 Gb MLC x4 | | | | |
| | KLMBG4GEUF-B04Q | | | | | |

NOTE: 1) P: $-40\text{ }^{\circ}\text{C} \leq T_c \leq 95\text{ }^{\circ}\text{C}$ (Default)
 Q: $-40\text{ }^{\circ}\text{C} \leq T_c \leq 105\text{ }^{\circ}\text{C}$

2.0 KEY FEATURES

- Embedded MultiMediaCard Ver. 5.1 compatible.
- SAMSUNG eMMC supports features of eMMC5.1 which are defined in JEDEC Standard
 - Supported Features : Packed command, Cache, Discard, Sanitize, Power Off Notification, Data Tag, Partition types, Context ID, Real Time Clock, Dynamic Device Capacity, HS200
 - Non-supported Features : Large Sector Size (4KB)
- Additional feature : HS400 mode (200MHz DDR)
- Full backward compatibility with previous MultiMediaCard system specification (1bit data bus, multi-eMMC systems)
- Data bus width : 1bit (Default), 4bit and 8bit
- MMC I/F Clock Frequency : 0 ~ 200MHz
 MMC I/F Boot Frequency : 0 ~ 52MHz
- Support Automotive Temperature ($-40\text{ }^{\circ}\text{C} \leq T_c \leq 95\text{ }^{\circ}\text{C}/105\text{ }^{\circ}\text{C}$)
 - 15th digit stands for below
 - P: $-40\text{ }^{\circ}\text{C} \leq T_c \leq 95\text{ }^{\circ}\text{C}$
 - Q: $-40\text{ }^{\circ}\text{C} \leq T_c \leq 105\text{ }^{\circ}\text{C}$
 - Based on Samsung Automotive Mission Profile, refer to Qual Report for more detail.
- Power : Interface power $\rightarrow V_{DD}(V_{CCQ})$ (1.70V ~ 1.95V or 2.7V ~ 3.6V), Memory power $\rightarrow V_{DDF}(V_{CC})$ (2.7V ~ 3.6V)

IF THERE IS ANY OTHER OPERATION TO IMPLEMENT IN ADDITION TO SPECIFICATION IN THE DATASHEET OR JEDEC STANDARD, PLEASE CONTACT EACH BRANCH OFFICE OR HEADQUARTERS OF SAMSUNG ELECTRONICS.

3.1.1 11.5mm x 13mm x 0.8mm Package Dimension

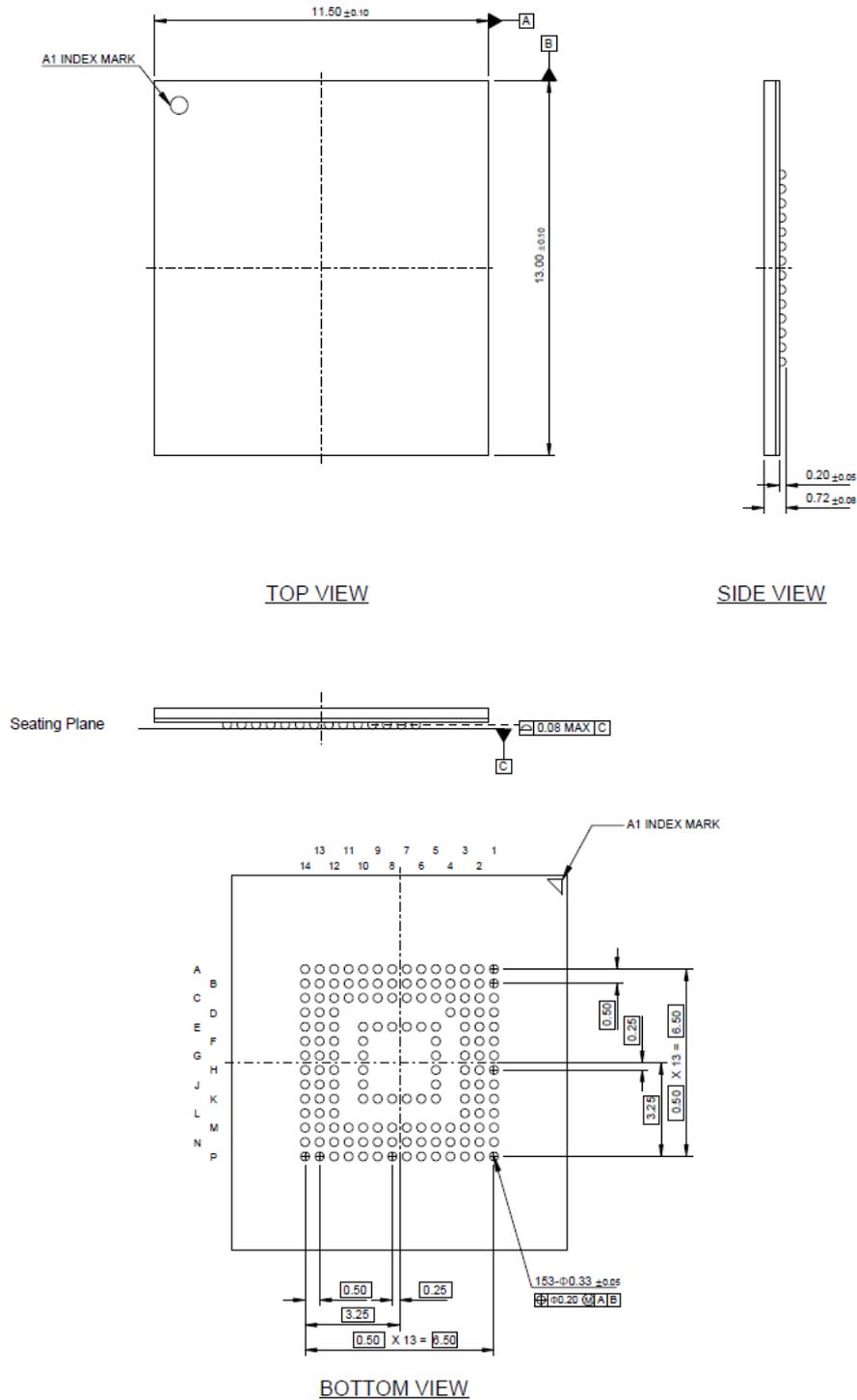


Figure 2. 11.5mm x 13mm x 0.8mm Package Dimension

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3.2 Product Architecture

- eMMC consists of NAND Flash and Controller. V_{DD} (V_{CCQ}) is for Controller power and V_{DDF} (V_{CC}) is for flash power.

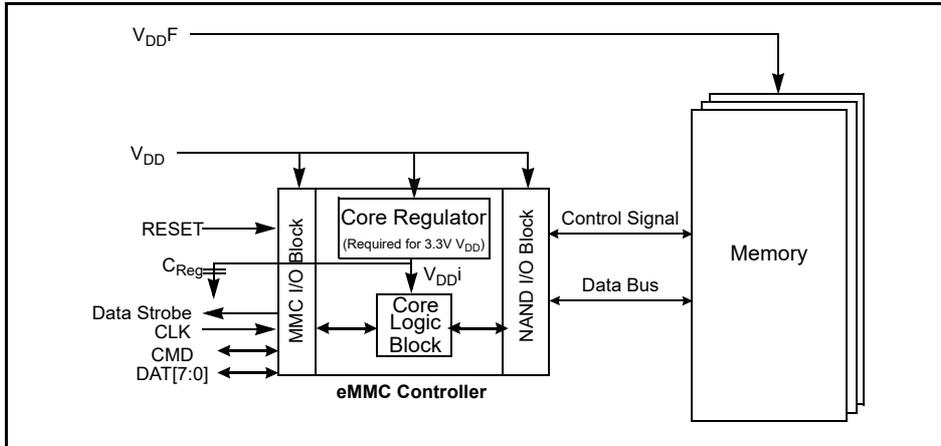


Figure 3. eMMC Block Diagram

4.0 HS400 Mode

eMMC5.0 product supports high speed DDR interface timing mode up to 400MB/s with 1.8V I/O supply.

HS400 mode supports the following features :

- DDR Data sampling method
- CLK frequency up to 200MHz
- Only 8-bits bus width available
- Signaling levels of 1.8V
- Five selectable Drive Strength (refer to the table below)

[Table 3] I/O Driver Strength Types (EXT_CSD register : DRIVER_STRENGTH [197])

| Driver Type | HS200 & HS400 Support | Nominal Impedance | Approximated driving capability compared to Type-0 | Remark |
|-------------|-----------------------|-------------------|----------------------------------------------------|-------------------------------------------------------------------------------------------|
| 0 | Default | 50Ω | x1 | Default Driver Type. Supports up to 200MHz operation. |
| 1 | Optional | 33Ω | x1.5 | Supports up to 200MHz Operation. |
| 2 | Optional | 66Ω | x0.75 | The weakest driver that supports up to 200MHz operation. |
| 3 | Optional | 100Ω | x0.5 | For low noise and low EMI systems. Maximal operating frequency is decided by Host design. |
| 4 | Optional | 40Ω | x1.2 | Supports up to 200MHz DDR operation |

NOTE :
 1) Device Type-0 is defined as mandatory for eMMC HS200 and HS400 while four additional Driver Types (1, 2, 3 and 4) are defined as optional, to allow the support of wider Host leads.

[Table 4] Device Type Values (EXT_CSD register : DEVICE_TYPE [196])

| Bit | Device Type | Supportability |
|-----|---------------------------------------------------------|----------------|
| 7 | HS400 Dual Data Rate eMMC @ 200 MHz - 1.2V I/O | Not support |
| 6 | HS400 Dual Data Rate eMMC @ 200 MHz - 1.8V I/O | Support |
| 5 | HS200 Single Data Rate eMMC @ 200 MHz - 1.2V I/O | Not support |
| 4 | HS200 Single Data Rate eMMC @ 200 MHz - 1.8V I/O | Support |
| 3 | High-Speed Dual Data Rate eMMC @ 52MHz - 1.2V I/O | Not support |
| 2 | High-Speed Dual Data Rate eMMC @ 52MHz - 1.8V or 3V I/O | Support |
| 1 | High-Speed eMMC @ 52MHz - at rated device voltage(s) | Support |
| 0 | High-Speed eMMC @ 26MHz - at rated device voltage(s) | Support |

[Table 5] Extended CSD Revisions (EXT_CSD register : EXT_CSD_REV [192])

| Value | Timing Interface | EXT_CSD Register Value |
|-------|------------------------------------|------------------------|
| 255-9 | Reserved | - |
| 8 | Revision 1.8 (for MMC V5.1) | 0x08 |
| 7 | Revision 1.7 (for MMC V5.0) | - |
| 6 | Revision 1.6 (for MMC V4.5, V4.51) | - |
| 5 | Revision 1.5 (for MMC V4.41) | - |
| 4 | Revision 1.4 (Obsolete) | - |
| 3 | Revision 1.3 (for MMC V4.3) | - |
| 2 | Revision 1.2 (for MMC V4.2) | - |
| 1 | Revision 1.1 (for MMC V4.1) | - |
| 0 | Revision 1.0 (for MMC V4.0) | - |

[Table 6] High Speed Timing Values (EXT_CSD register : HS_TIMING [185])

| Value | Timing Interface | Supportability |
|-------|----------------------------------------------------|----------------|
| 0x0 | Selecting backwards compatibility interface timing | Support |
| 0x1 | High Speed | Support |
| 0x2 | HS200 | Support |
| 0x3 | HS400 | Support |

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5.0 New eMMC5.1 Features

5.1 Overview

| New Feature | JEDEC | Support |
|------------------------------|-----------|---------|
| Cache Flushing Report | Mandatory | Yes |
| Background operation control | Mandatory | Yes |
| Command Queuing | Optional | Yes |
| Enhanced Strobe | Optional | Yes |
| RPMB Throughput improve | Optional | Yes |
| Secure Write Protection | Optional | Yes |

5.2 Command Queuing

To facilitate command queuing in eMMC, the device manages an internal task queue that the host can queue during data transfer tasks.

Every task is issued by the host and initially queued as pending. The device works to prepare pending tasks for execution. When a task is ready for execution, its state changes to "ready for execution".

The host tracks the state of all queued tasks and may order the execution of any task, marked as "ready for execution", by sending a command indicating its task ID. The device executes the data transfer transaction after receiving the execute command(CMD46/CMD47)

5.2.1 CMD Set Description

[Table 7] CMD Set Description and Details

| CMD | Type | Argument | Abbreviation | Purpose |
|-------|---------|-------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|---------------------|-------------------------------------------------------------------------------------------------------------------------------------------------------|
| CMD44 | ac/R1 | [31] Reliable Write Request [30] DAT_DIR - "0" write / "1" read [29] tag request [28:25] context ID [24] forced programming [23] Priority: "0" simple / "1" high [20:16] TASK ID [15:0] number of blocks | QUEUED_TASK_PARAMS | Define direction of operation (Read or Write) and Set high priority CMD Queue with task ID |
| CMD45 | ac/R1 | [31:0] Start block address | QUEUED_TASK_ADDRESS | Indicate data address for Queued CMD |
| CMD46 | adtc/R1 | [20:16] TASK ID | EXECUTE_READ_TASK | (Read) Transmit the requested number of data blocks |
| CMD47 | adtc/R1 | [20:16] TASK ID | EXECUTE_WRITE_TASK | (Write) Transmit the requested number of data blocks |
| CMD48 | ac/R1b | [20:16] Task ID [3:0] TM op-code | CMDQ_TASK_MGMT | Reset a specific task or entire queue. [20:16] when TM op-code = 2h these bits represent TaskID. When TM op-code = 1h these bits are reserved." |

5.2.2 New Response : QSR (Queue Status Register)

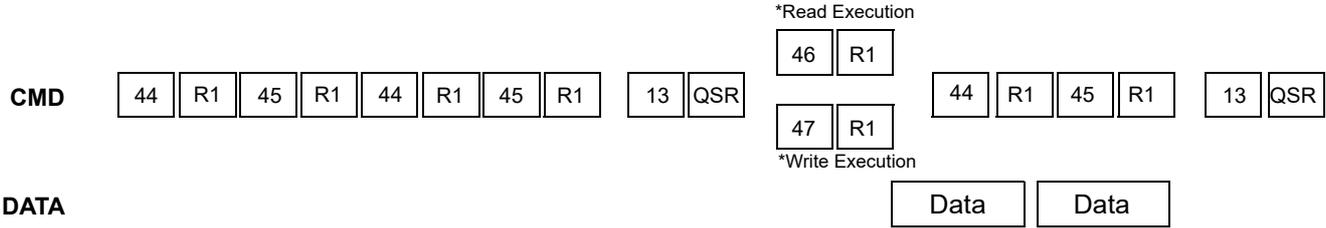
The 32-bit Queue Status Register (QSR) carries the state of tasks in the queue at a specific point in time. The host has read access to this register through device response to SEND_STATUS command (CMD13 with bit[15]="1"), R1's argument will be the 32-bit Queue Status Register (QSR). Every bit in the QSR represents the task whose ID corresponds to the bit index. If bit QSR[i] = "0", then the queued task with a Task ID i is not ready for execution. The task may be queued and pending, or the Task ID is unused. If bit QSR[i] = "1", then the queued task with Task ID i is ready for execution.

5.2.3 Send Status : CMD13

CMD13 for reading the Queue Status Register (QSR) by the host. If bit[15] in CMD13's argument is set to 1, then the device shall send an R1 Response with the QSR instead of the Device Status. * There is still legacy CMD13 with R` response

5.2.4 Mechanism of CMD Queue operation

Host issues CMD44 with Task ID number, Sector, Count, Direction, Priority to the device followed by CMD45 and host checks the Queue Status check with CMD13 [15]bits to 1 After that host issues CMD46 for Read or CMD47 for write During CMD queue operation, CMD44/CMD45 is able to be issued at anytime when the CMD line is not in use



5.2.5 CMD Queue Register description

Configuration and capability structures shall be added to the EXT_CSD register, as described below

[Table 8] CMD Queuing Support (EXT_CSD register : CMDQ_SUPPORT [308])

| Bit7 | Bit6 | Bit5 | Bit4 | Bit | Bit2 | Bit1 | Bit0 |
|----------|------|------|------|-----|------|------|--------------------------|
| Reserved | | | | | | | CMD Queue supportability |

This field indicates whether the device supports command queuing or not

- 0x0: CMD Queue function is not supported
- 0x1: CMD Queue function is supported

[Table 9] Command Queue Mode Enable(EXT_CSD register : CMDQ_MODE_EN [15])

| Bit7 | Bit6 | Bit5 | Bit4 | Bit | Bit2 | Bit1 | Bit0 |
|----------|------|------|------|-----|------|------|------|
| Reserved | | | | | | | - |

This field is used by the host enable command queuing

- 0x0: Queue function is not enabled
- 0x1: Queue function is enabled

[Table 10] CMD Queuing Depth(EXT_CSD register : CMDQ_DEPTH [307])

| Bit7 | Bit6 | Bit5 | Bit4 | Bit | Bit2 | Bit1 | Bit0 |
|----------|------|------|------|-----|------|------|------|
| Reserved | | | | N | | | |

This field is used to calculate the depth of the queue supported by the device

- Bit encoding:
- [7:5]: Reserved
- [4:0]: N,a parameter used to calculate the Queue Depth of task queue in the device.
- Queue Depth = N+1.

5.3 Enhanced Strobe Mode

This product supports Enhanced Strobe in HS400 mode and refer to the details as described in eMMC5.1 JEDEC standard

5.4 RPMB Throughput improve

[Table 11] Related parameter register in EXT_CSD : WR_REL_PARAM [166]

| Name | Field | Bit | Type |
|------------------------------|----------------|-----|------|
| Enhanced RPMB Reliable Write | EN_RPMB_REL_WR | 4 | R |

- Bit[4]: EN_RPMB_REL_WR(R)
- 0x0: RPMB transfer size is either 256B (single 512B frame) or 512B (Two 512B frame).
- 0 x1: RPMB transfer size is either 256B (single 512B frame), 512B (Two 512B frame), or 8KB(Thirty two 512B frames).

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5.5 Secure Write Protection

Configuration and capability structures shall be added to the EXT_CSD register and Authenticated Device Configuration Area as described below

[Table 12] Parameter register in EXT_CSD : SECURE_WP_INFO [211]

| Bit7 | Bit6 | Bit5 | Bit4 | Bit | Bit2 | Bit1 | Bit0 |
|----------|------|------|------|-----|------|---------------------|-------------------|
| Reserved | | | | | | SECURE_WP_EN_STATUS | SECURE_WP_SUPPORT |

Bit[7:2]: Reserved

Bit[1]: SECURE_WP_EN_STATUS(R)

0x0: Legacy Write Protection mode.

0x1: Secure Write Protection mode.

Bit[0]: SECURE_WP_SUPPORT(R)

0x0: Secure Write Protection is NOT supported by this device

0x1: Secure Write Protection is supported by this device

[Table 13] Authenticated Device Configuration Area[1] : SECURE_WP_MODE_ENABLE

| Bit7 | Bit6 | Bit5 | Bit4 | Bit | Bit2 | Bit1 | Bit0 |
|----------|------|------|------|-----|------|------|------|
| Reserved | | | | | | | 0x00 |

Bit[7:1] : Reserved

Bit[0] : SECURE_WP_EN (R/W/E)

The default value of this field is 0x0.

- 0x0 : Legacy Write Protection mode, i.e., TMP_WRITE_PROTECT[12] , PERM_WRITE_PROTECT[13] is updated by CMD27. USER_WP[171], BOOT_WP[173] and BOOT_WP_STATUS[174] are updated by CMD6.
- 0x1 : Secure Write Protection mode. The access to the write protection related EXT_CSD and CSD fields depends on the value of SECURE_WP_MASK bit in SECURE_WP_MODE_CONFIG field.

[Table 14] Authenticated Device Configuration Area[2] : SECURE_WP_MODE_CONFIG

| Bit7 | Bit6 | Bit5 | Bit4 | Bit | Bit2 | Bit1 | Bit0 |
|----------|------|------|------|-----|------|------|------|
| Reserved | | | | | | | 0x00 |

Bit[7:1] : Reserved

Bit[0] : SECURE_WP_MASK (R/W/E_P)

The default value of this field is 0x0.

- 0x0: Disabling updating WP related EXT_CSD and CSD fields. CMD27 (Program CSD) will generate generic error for setting TMP_WRITE_PROTECT[12] , PERM_WRITE_PROTECT[13]. CMD6 for updating USER_WP[171], BOOT_WP[173] and BOOT_WP_STATUS[174] generates SWITCH_ERROR. If a force erase command is issued, the command will fail (Device stays locked) and the LOCK_UNLOCK_FAILED error bit will be set in the status register. If CMD28 or CMD29 is issued, then generic error will be occurred. Power-on Write Protected boot partitions will keep protected mode after power failure, H/W reset assertion and any CMD0 reset. The device keeps the current value of BOOT_WP_STATUS in the EXT_CSD register to be same after power cycle, H/W reset assertion, and any CMD0 reset.
- 0x1: Enabling updating WP related EXT_CSD and CSD fields. I.e TMP_WRITE_PROTECT[12] , PERM_WRITE_PROTECT[13] , USER_WP[171], BOOT_WP[173] and BOOT_WP_STATUS[174] are accessed using CMD6, CMD8 and CMD27. If a force erase command is issued and accepted, then ALL THE DEVICE CONTENT WILL BE ERASED including the PWD and PWD_LEN register content and the locked Device will get unlocked. If a force erase command is issued and power-on protected or a permanently-write-protected write protect groups exist on the device, the command will fail (Device stays locked) and the LOCK_UNLOCK_FAILED error bit will be set in the status register. An attempt to force erase on an unlocked Device will fail and LOCK_UNLOCK_FAILED error bit will be set in the status register. Write Protection is applied to the WPG indicated by CMD28 with the WP type indicated by the bit[2] and bit[0] of USER_WP[171]. All temporary WP Groups and power-on Write Protected boot partitions become writable/erasable temporarily which means write protect type is not changed. All power-on and permanent WP Groups in user area will not become writable/erasable temporarily. Those temporarily writable/erasable area will become write protected when this bit is cleared to 0x0 by the host or when there is power failure, H/W reset assertion and any CMD0 reset. The device keeps the current value of BOOT_WP_STATUS in the EXT_CSD register to be same after power cycle, H/W reset assertion, and any CMD0 reset.

6.0 Technical Notes

6.1 S/W Algorithm

6.1.1 Partition Management

The device initially consists of two Boot Partitions and RPMB Partition and User Data Area.

The User Data Area can be divided into four General Purpose Area Partitions and User Data Area partition. Each of the General Purpose Area partitions and a section of User Data Area partition can be configured as enhanced partition.

6.1.1.1 Enhanced Partition (Area)

SAMSUNG eMMC adopts Enhanced User Data Area as SLC Mode. Therefore when master adopts some portion as enhanced user data area in User Data Area, that area occupies double size of original set up size. (Ex. if master set 1MB for enhanced mode, total 2MB user data area is needed to generate 1MB enhanced area)

Max Enhanced User Data Area size is defined as. $(MAX_ENH_SIZE_MULT \times HC_WP_GRP_SIZE \times HC_ERASE_GRP_SIZE \times 512kBytes)$

6.1.2 Boot Operation

Device supports not only boot mode but also alternative boot mode. Device supports high speed timing and dual data rate during boot.

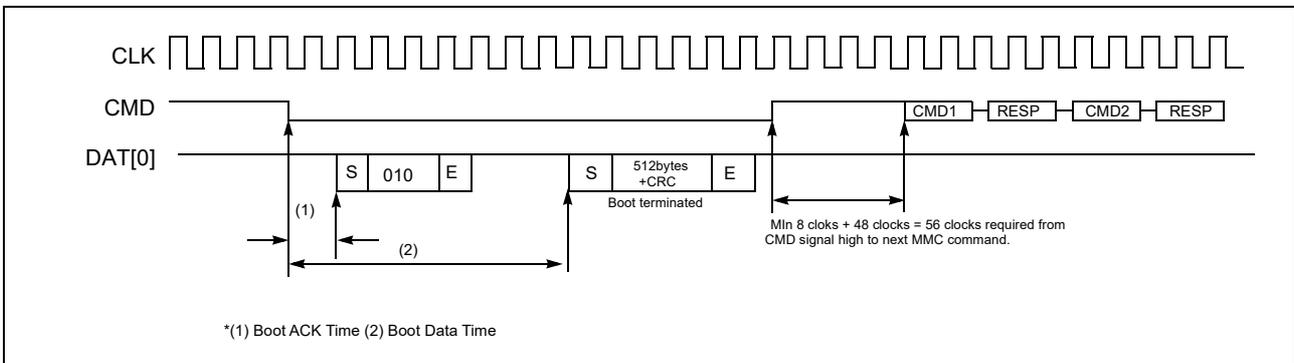


Figure 4. Embedded MultiMediaCard State Diagram (Boot Mode)

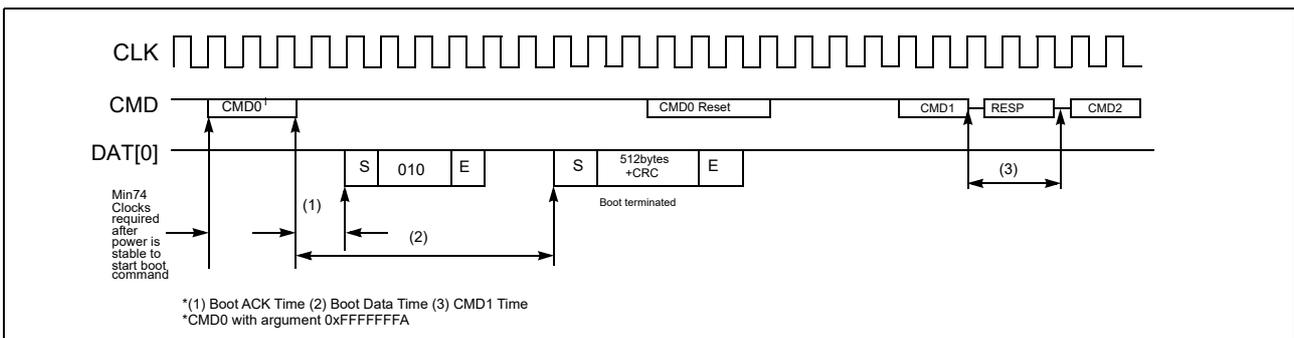


Figure 5. Embedded MultiMediaCard State Diagram (Alternative Boot Mode)

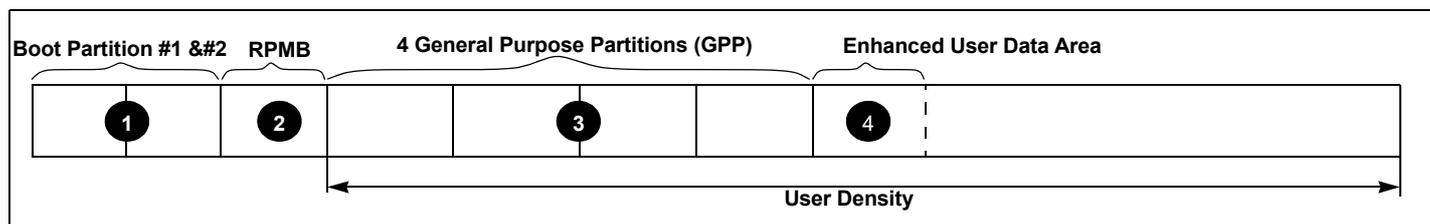
[Table 15] Boot ack, boot data and initialization Time

| Timing Factor | | Value | |
|---------------------|--------|---------|---------------|
| Boot ACK Time | | < 10 ms | |
| Boot Data Time | | < 28 ms | |
| Initialization Time | PON | 8 GB | 50 ms (Typ.) |
| | | 16 GB | 50 ms (Typ.) |
| | | 32 GB | 60 ms (Typ.) |
| | NO PON | 8 GB | 200 ms (Typ.) |
| | | 16 GB | 300 ms (Typ.) |
| | | 32GB | 400 ms (Typ.) |

NOTE :
 1) This initialization time indicates the normal initialization time (without partition setting). Please refer to INI_TIMEOUT_AP[241] in EXT_CSD for the 1st initialization time including initial partition setting.(by samsung test pattern)

6.1.3 User Density

Total User Density depends on device type. For example, 32MB in the SLC Mode requires 64MB in MLC. This results in decreasing of user density.



[Table 16] Capacity According To Partition

| | | Boot partition 1 | Boot partition 2 | RPMB |
|-------|---------|------------------|------------------|----------|
| 8 GB | Default | 32,640 KB | 32,640 KB | 4,096 KB |
| | Max | 32,640 KB | 32,640 KB | 4,096 KB |
| 16 GB | Default | 32,640 KB | 32,640 KB | 4,096 KB |
| | Max | 32,640 KB | 32,640 KB | 4,096 KB |
| 32 GB | Default | 32,640 KB | 32,640 KB | 4,096 KB |
| | Max | 32,640 KB | 32,640 KB | 4,096 KB |

[Table 17] Maximum Enhanced Partition Size

| Device | Max. Enhanced Partition Size |
|--------|------------------------------|
| 8 GB | 3,909,091,328 |
| 16 GB | 7,818,182,656 |
| 32 GB | 15,636,365,312 |

[Table 18] User Density Size

| Device | User Density Size |
|--------|-------------------|
| 8 GB | 7,818,182,656 |
| 16 GB | 15,636,365,312 |
| 32 GB | 31,272,730,624 |

6.1.4 Performance

[Table 19] Performance

| Density | Sequential Read (MB/s) | Sequential Write (MB/s) |
|---------|------------------------|-------------------------|
| 8 GB | 330 | 40 |
| 16 GB | | 75 |
| 32 GB | | 150 |

* Test Condition : Bus width x8, HS400, 512KB data transfer, Packed Off, Cache On, w/o file system overhead, measured on Samsung's internal board.

7.0 REGISTER VALUE

7.1 OCR Register

The 32-bit operation conditions register stores the V_{DD} voltage profile of the eMMC. In addition, this register includes a status information bit. This status bit is set if the eMMC power up procedure has been finished. The OCR register shall be implemented by all eMMCs.

[Table 20] OCR Register

| OCR bit | V_{DD} voltage window ²⁾ | Register Value |
|---------|---------------------------------------|------------------------------------------------------------|
| [6:0] | Reserved | 00 00000b |
| [7] | 1.70 - 1.95 | 1b |
| [14:8] | 2.0-2.6 | 000 0000b |
| [23:15] | 2.7-3.6 | 1 1111 1111b |
| [28:24] | Reserved | 0 0000b |
| [30:29] | Access Mode | 00b (byte mode) 10b (sector mode) -[*Higher than 2GB only] |
| [31] | | eMMC power up status bit (busy) ¹⁾ |

NOTE :

- 1) This bit is set to LOW if the eMMC has not finished the power up routine
- 2) The voltage for internal flash memory(V_{DDF}) should be 2.7-3.6v regardless of OCR Register value.

7.2 CID Register

[Table 21] CID Register

| Name | Field | Width | CID-slice | CID Value |
|-----------------------|-------|-------|-----------|------------------------|
| Manufacturer ID | MID | 8 | [127:120] | 0x15 |
| Reserved | | 6 | [119:114] | --- |
| Card/BGA | CBX | 2 | [113:112] | 01 |
| OEM/Application ID | OID | 8 | [111:104] | --- ¹ |
| Product name | PNM | 48 | [103:56] | See Product name table |
| Product revision | PRV | 8 | [55:48] | --- ² |
| Product serial number | PSN | 32 | [47:16] | --- ³ |
| Manufacturing date | MDT | 8 | [15:8] | --- ⁴ |
| CRC7 checksum | CRC | 7 | [7:1] | --- ⁵ |
| not used, always '1' | - | 1 | [0:0] | --- |

NOTE :

- 1),4),5) description are same as eMMC JEDEC standard.
- 2) PRV is composed of the revision count of controller and the revision count of F/W patch.
- 3) A 32 bits unsigned binary integer. (Random Number)

7.2.1 Product Name Table (In CID Register)

[Table 22] Product Name Table

| Part Number | Density | Product Name in CID Register (PNM) |
|-----------------|---------|------------------------------------|
| KLM8G1GEUF-B04x | 8 GB | 0 x 384755463452 |
| KLMAG2GEUF-B04x | 16 GB | 0 x 414755463452 |
| KLMBG4GEUF-B04x | 32 GB | 0 x 424755463452 |

7.3 CSD Register

The Card-Specific Data register provides information on how to access the eMMC contents. The CSD defines the data format, error correction type, maximum data access time, data transfer speed, whether the DSR register can be used etc. The programmable part of the register (entries marked by W or E, see below) can be changed by CMD27. The type of the entries in the table below is coded as follows:

R : Read only

W: One time programmable and not readable.

R/W: One time programmable and readable.

W/E : Multiple writable with value kept after power failure, H/W reset assertion and any CMD0 reset and not readable.

R/W/E: Multiple writable with value kept after power failure, H/W reset assertion and any CMD0 reset and readable.

R/W/C_P: Writable after value cleared by power failure and HW/ rest assertion (the value not cleared by CMD0 reset) and readable.

R/W/E_P: Multiple writable with value reset after power failure, H/W reset assertion and any CMD0 reset and readable.

W/E/_P: Multiple writable with value reset after power failure, H/W reset assertion and any CMD0 reset and not readable.

[Table 23] CSD Register

| Name | Field | Width | Cell Type | CSD-slice | CSD Value | | |
|--------------------------------------------------|--------------------|-------|-----------|-----------|-----------|-------|-------|
| | | | | | 8 GB | 16 GB | 32 GB |
| CSD structure | CSD_STRUCTURE | 2 | R | [127:126] | 0x03 | | |
| System specification version | SPEC_VERS | 4 | R | [125:122] | 0x04 | | |
| Reserved | - | 2 | R | [121:120] | - | | |
| Data read access-time 1 | TAAC | 8 | R | [119:112] | 0x27 | | |
| Data read access-time 2 in CLK cycles (NSAC*100) | NSAC | 8 | R | [111:104] | 0x01 | | |
| Max. bus clock frequency | TRAN_SPEED | 8 | R | [103:96] | 0x32 | | |
| Device command classes | CCC | 12 | R | [95:84] | 0xF5 | | |
| Max. read data block length | READ_BL_LEN | 4 | R | [83:80] | 0x09 | | |
| Partial blocks for read allowed | READ_BL_PARTIAL | 1 | R | [79:79] | 0x00 | | |
| Write block misalignment | WRITE_BLK_MISALIGN | 1 | R | [78:78] | 0x00 | | |
| Read block misalignment | READ_BLK_MISALIGN | 1 | R | [77:77] | 0x00 | | |
| DSR implemented | DSR_IMP | 1 | R | [76:76] | 0x00 | | |
| Reserved | - | 2 | R | [75:74] | - | | |
| Device size | C_SIZE | 12 | R | [73:62] | 0xFFF | | |
| Max. read current @ V _{DD} min | VDD_R_CURR_MIN | 3 | R | [61:59] | 0x06 | | |
| Max. read current @ V _{DD} max | VDD_R_CURR_MAX | 3 | R | [58:56] | 0x06 | | |
| Max. write current @ V _{DD} min | VDD_W_CURR_MIN | 3 | R | [55:53] | 0x06 | | |
| Max. write current @ V _{DD} max | VDD_W_CURR_MAX | 3 | R | [52:50] | 0x06 | | |
| Device size multiplier | C_SIZE_MULT | 3 | R | [49:47] | 0x07 | | |
| Erase group size | ERASE_GRP_SIZE | 5 | R | [46:42] | 0x1F | | |
| Erase group size multiplier | ERASE_GRP_MULT | 5 | R | [41:37] | 0x1F | | |
| Write protect group size | WP_GRP_SIZE | 5 | R | [36:32] | 0x0F | | |
| Write protect group enable | WP_GRP_ENABLE | 1 | R | [31:31] | 0x01 | | |
| Manufacturer default ECC | DEFAULT_ECC | 2 | R | [30:29] | 0x00 | | |
| Write speed factor | R2W_FACTOR | 3 | R | [28:26] | 0x03 | | |
| Max. write data block length | WRITE_BL_LEN | 4 | R | [25:22] | 0x09 | | |
| Partial blocks for write allowed | WRITE_BL_PARTIAL | 1 | R | [21:21] | 0x00 | | |
| Reserved | - | 4 | R | [20:17] | - | | |
| Content protection application | CONTENT_PROT_APP | 1 | R | [16:16] | 0x00 | | |
| File format group | FILE_FORMAT_GRP | 1 | R/W | [15:15] | 0x00 | | |
| Copy flag (OTP) | COPY | 1 | R/W | [14:14] | 0x01 | | |
| Permanent write protection | PERM_WRITE_PROTECT | 1 | R/W | [13:13] | 0x00 | | |
| Temporary write protection | TMP_WRITE_PROTECT | 1 | R/W/E | [12:12] | 0x00 | | |
| File format | FILE_FORMAT | 2 | R/W | [11:10] | 0x00 | | |
| ECC code | ECC | 2 | R/W/E | [9:8] | 0x00 | | |
| CRC | CRC | 7 | R/W/E | [7:1] | - | | |
| Not used, always '1' | - | 1 | — | [0:0] | - | | |

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7.4 Extended CSD Register

The Extended CSD register defines the eMMC properties and selected modes. It is 512 bytes long. The most significant 320 bytes are the Properties segment, which defines the eMMC capabilities and cannot be modified by the host. The lower 192 bytes are the Modes segment, which defines the configuration the eMMC is working in. These modes can be changed by the host by means of the SWITCH command.

R : Read only

W: One time programmable and not readable.

R/W: One time programmable and readable.

W/E : Multiple writable with value kept after power failure, H/W reset assertion and any CMD0 reset and not readable.

R/W/E: Multiple writable with value kept after power failure, H/W reset assertion and any CMD0 reset and readable.

R/W/C_P: Writable after value cleared by power failure and HW/ reset assertion (the value not cleared by CMD0 reset) and readable.

R/W/E_P: Multiple writable with value reset after power failure, H/W reset assertion and any CMD0 reset and readable.

W/E/_P: Multiple writable with value reset after power failure, H/W reset assertion and any CMD0 reset and not readable

[Table 24] Extended CSD Register

| Name | Field | Size (Bytes) | Cell Type | CSD-slice | CSD Value | | |
|-------------------------------------------|-------------------------------------------|--------------|-----------|-----------|---------------|------|------|
| | | | | | 8GB | 16GB | 32GB |
| Properties Segment | | | | | | | |
| Reserved | | 6 | - | [511:506] | - | | |
| Extended Security Commands Error | EXT_SECURITY_ERR | 1 | R | [505] | 0x00 | | |
| Supported Command Sets | S_CMD_SET | 1 | R | [504] | 0x01 | | |
| HPI features | HPI_FEATURES | 1 | R | [503] | 0x01 | | |
| Background operations support | BKOPS_SUPPORT | 1 | R | [502] | 0x01 | | |
| Max packed read commands | MAX_PACKED_READS | 1 | R | [501] | 0x3F | | |
| Max packed write commands | MAX_PACKED_WRITES | 1 | R | [500] | 0x3F | | |
| Data Tag Support | DATA_TAG_SUPPORT | 1 | R | [499] | 0x01 | | |
| Tag Unit Size | TAG_UNIT_SIZE | 1 | R | [498] | 0x02 | | |
| Tag Resources Size | TAG_RES_SIZE | 1 | R | [497] | 0x00 | | |
| Context management capabilities | CONTEXT_CAPABILITIES | 1 | R | [496] | 0x05 | | |
| Large Unit size | LARGE_UNIT_SIZE_M1 | 1 | R | [495] | 0x07 | | |
| Extended partitions attribute support | EXT_SUPPORT | 1 | R | [494] | 0x03 | | |
| Supported modes | SUPPORTED_MODES | 1 | R | [493] | 0x03 | | |
| FFU features | FFU_FEATURES | 1 | R | [492] | 0x00 | | |
| Operation codes timeout | OPERATION_CODE_TIMEOUT | 1 | R | [491] | 0x00 | | |
| FFU Argument | FFU_ARG | 4 | R | [490:487] | 0xC7810000 | | |
| Barrier support | BARRIER_SUPPORT | 1 | R | [486] | 0x00 | | |
| Reserved | | 177 | - | [485:309] | - | | |
| CMD Queuing Support | CMDQ_SUPPORT | 1 | R | [308] | 0x01 | | |
| CMD Queuing Depth | CMDQ_DEPTH | 1 | R | [307] | 0x0F | | |
| Reserved | | 1 | - | [306] | - | | |
| Number of FW sectors correctly programmed | NUMBER_OF_FW_SECTORS_CORRECTLY_PROGRAMMED | 4 | R | [305:302] | 0x00 | | |
| Vendor proprietary health report | VENDOR_PROPRIETARY_HEALTH_REPORT | 32 | R | [301:270] | 0x00 | | |
| Device life time estimation type B | DEVICE_LIFE_TIME_EST_TYP_B | 1 | R | [269] | 0x01 | | |
| Device life time estimation type A | DEVICE_LIFE_TIME_EST_TYP_A | 1 | R | [268] | 0x01 | | |
| Pre EOL information | PRE_EOL_INFO | 1 | R | [267] | 0x01 | | |
| Optimal read size | OPTIMAL_READ_SIZE | 1 | R | [266] | 0x00 | | |
| Optimal write size | OPTIMAL_WRITE_SIZE | 1 | R | [265] | 0x08 | 0x10 | 0x20 |
| Optimal trim unit size | OPTIMAL_TRIM_UNIT_SIZE | 1 | R | [264] | 0x01 | | |
| Device version | DEVICE_VERSION | 2 | R | [263:262] | 0x00 | | |
| Firmware version | FIRMWARE_VERSION | 8 | R | [261:254] | FW Patch Ver. | | |
| Power class for 200MHz, DDR at VCC=3.6V | PWR_CL_DDR_200_360 | 1 | R | [253] | 0x00 | | |
| Cache size | CACHE_SIZE | 4 | R | [252:249] | 0x10000 | | |

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| | | | | | | | |
|-------------------------------------------------------------------|---------------------------------------------|---|---|-----------|---------------|---------------|---------------|
| Generic CMD6 timeout | GENERIC_CMD6_TIME | 1 | R | [248] | 0x0A | | |
| Power off notification (long) timeout | POWER_OFF_LONG_TIME | 1 | R | [247] | 0x3C | | |
| Background operations status | BKOPS_STATUS | 1 | R | [246] | 0x00 | | |
| Number of correctly programmed sectors | CORRECTLY_PRG_SECTORS_NUM | 4 | R | [245:242] | 0x00 | | |
| 1st initialization time after partitioning | INI_TIMEOUT_AP | 1 | R | [241] | 0x1E | | |
| Cache Flushing Policy | CACHE_FLUSH_POLICY | 1 | R | [240] | 0x00 | | |
| Power class for 52MHz, DDR at Vcc=3.6V | PWR_CL_DDR_52_360 | 1 | R | [239] | 0x00 | | |
| Power class for 52MHz, DDR at Vcc=1.95V | PWR_CL_DDR_52_195 | 1 | R | [238] | 0x00 | | |
| Power class for 200MHz at Vccq=1.95V, Vcc=3.6V | PWR_CL_200_195 | 1 | R | [237] | 0x00 | | |
| Power class for 200MHz, at Vccq=1.3V, Vcc=3.6V | PWR_CL_200_130 | 1 | R | [236] | 0x00 | | |
| Minimum Write Performance for 8bit at 52MHz in DDR mode | MIN_PERF_DDR_W_8_52 | 1 | R | [235] | 0x00 | | |
| Minimum Read Performance for 8bit at 52MHz in DDR mode | MIN_PERF_DDR_R_8_52 | 1 | R | [234] | 0x00 | | |
| Reserved | | 1 | - | [233] | - | | |
| TRIM Multiplier | TRIM_MULT | 1 | R | [232] | 0x02 | | |
| Secure Feature support | SEC_FEATURE_SUPPORT | 1 | R | [231] | 0x55 | | |
| Secure Erase Multiplier | SEC_ERASE_MULT | 1 | R | [230] | 0x1B | | |
| Secure TRIM Multiplier | SEC_TRIM_MULT | 1 | R | [229] | 0x11 | | |
| Boot information | BOOT_INFO | 1 | R | [228] | 0x07 | | |
| Reserved | | 1 | - | [227] | - | | |
| Boot partition size | BOOT_SIZE_MULT | 1 | R | [226] | 0xFF | | |
| Access size | ACC_SIZE | 1 | R | [225] | 0x07 | | |
| High-capacity erase unit size | HC_ERASE_GRP_SIZE | 1 | R | [224] | 0x01 | | |
| High-capacity erase timeout | ERASE_TIMEOUT_MULT | 1 | R | [223] | 0x01 | | |
| Reliable write sector count | REL_WR_SEC_C | 1 | R | [222] | 0x01 | | |
| High-capacity write protect group size | HC_WP_GRP_SIZE | 1 | R | [221] | 0x10 | | |
| Sleep current (VCC) | S_C_VCC | 1 | R | [220] | 0x07 | | |
| Sleep current (VCCQ) | S_C_VCCQ | 1 | R | [219] | 0x07 | | |
| Production state awareness timeout | PRODUCTION_STATE_AWARE- NESS_ TIMEOUT | 1 | R | [218] | 0x00 | | |
| Sleep/awake timeout | S_A_TIMEOUT | 1 | R | [217] | 0x11 | | |
| Sleep Notification Timeout | SLEEP_NOTIFICATION_TIME | 1 | R | [216] | 0x07 | | |
| Sector Count | SEC_COUNT | 4 | R | [215:212] | 0x0E90 000 | 0x1D20 000 | 0x3A40 000 |
| Secure Write Protect Information | SECURE_WP_INFO | 1 | R | [211] | 0x01 | | |
| Minimum Write Performance for 8bit at 52MHz | MIN_PERF_W_8_52 | 1 | R | [210] | 0x00 | | |
| Minimum Read Performance for 8bit at 52MHz | MIN_PERF_R_8_52 | 1 | R | [209] | 0x00 | | |
| Minimum Write Performance for 8bit at 26MHz, for 4bit at 52MHz | MIN_PERF_W_8_26_4_52 | 1 | R | [208] | 0x00 | | |
| Minimum Read Performance for 8bit at 26MHz, for 4bit at 52MHz | MIN_PERF_R_8_26_4_52 | 1 | R | [207] | 0x00 | | |
| Minimum Write Performance for 4bit at 26MHz | MIN_PERF_W_4_26 | 1 | R | [206] | 0x00 | | |
| Minimum Read Performance for 4bit at 26MHz | MIN_PERF_R_4_26 | 1 | R | [205] | 0x00 | | |
| Reserved | | 1 | - | [204] | - | | |
| Power class for 26MHz at 3.6V 1 R | PWR_CL_26_360 | 1 | R | [203] | 0x00 | | |
| Power class for 52MHz at 3.6V 1 R | PWR_CL_52_360 | 1 | R | [202] | 0x00 | | |
| Power class for 26MHz at 1.95V 1 R | PWR_CL_26_195 | 1 | R | [201] | 0x00 | | |
| Power class for 52MHz at 1.95V 1 R | PWR_CL_52_195 | 1 | R | [200] | 0x00 | | |

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| | | | | | |
|----------------------------------------|-----------------------|---|-------------------------------------|-------|------|
| Partition switching timing | PARTITION_SWITCH_TIME | 1 | R | [199] | 0x01 |
| Out-of-interrupt busy timing | OUT_OF_INTERRUPT_TIME | 1 | R | [198] | 0x02 |
| I/O Driver Strength | DRIVER_STRENGTH | 1 | R | [197] | 0x1F |
| Device type | DEVICE_TYPE | 1 | R | [196] | 0x57 |
| Reserved | | 1 | - | [195] | - |
| CSD Structure | CSD_STRUCTURE | 1 | R | [194] | 0x02 |
| Reserved | | 1 | - | [193] | - |
| Extended CSD revision | EXT_CSD_REV | 1 | R | [192] | 0x08 |
| Modes Segment | | | | | |
| Command set | CMD_SET | 1 | R/W/ E_P | [191] | 0x00 |
| Reserved | | 1 | - | [190] | - |
| Command set revision | CMD_SET_REV | 1 | R | [189] | 0x00 |
| Reserved | | 1 | - | [188] | - |
| Power class | POWER_CLASS | 1 | R/W/ E_P | [187] | 0x00 |
| Reserved | | 1 | - | [186] | - |
| High-speed interface timing | HS_TIMING | 1 | R/W/ E_P | [185] | 0x01 |
| Strobe Support | STROBE_SUPPORT | 1 | R | [184] | 0x01 |
| Bus width mode | BUS_WIDTH | 1 | W/E_P | [183] | 0x00 |
| Reserved | | 1 | - | [182] | - |
| Erased memory content | ERASED_MEM_CONT | 1 | R | [181] | 0x00 |
| Reserved | | 1 | - | [180] | - |
| Partition configuration | PARTITION_CONFIG | 1 | R/W/E & R/W/ E_P | [179] | 0x00 |
| Boot config protection | BOOT_CONFIG_PROT | 1 | R/W & R/W/ C_P | [178] | 0x00 |
| Boot bus Conditions | BOOT_BUS_CONDITIONS | 1 | R/W/E | [177] | 0x00 |
| Reserved | | 1 | - | [176] | - |
| High-density erase group definition | ERASE_GROUP_DEF | 1 | R/W/ E_P | [175] | 0x00 |
| Boot write protection status registers | BOOT_WP_STATUS | 1 | R | [174] | 0x00 |
| Boot area write protection register | BOOT_WP | 1 | R/W & R/W/ C_P | [173] | 0x00 |
| Reserved | | 1 | - | [172] | - |
| User area write protection register | USER_WP | 1 | R/W, R/W/ C_P &R/W/ E_P | [171] | 0x00 |
| Reserved | | 1 | - | [170] | - |
| FW configuration | FW_CONFIG | 1 | R/W | [169] | 0x00 |
| RPMB Size | RPMB_SIZE_MULT | 1 | R | [168] | 0x20 |
| Write reliability setting register | WR_REL_SET | 1 | R/W | [167] | 0x1F |
| Write reliability parameter register | WR_REL_PARAM | 1 | R | [166] | 0x14 |
| Start Sanitize operation | SANITIZE_START | 1 | W/E_P | [165] | 0x00 |
| Manually start background operations | BKOPS_START | 1 | W/E_P | [164] | 0x00 |
| Enable background operations handshake | BKOPS_EN | 1 | R/W | [163] | 0x00 |
| H/W reset function | RST_n_FUNCTION | 1 | R/W | [162] | 0x00 |
| HPI management | HPI_MGMT | 1 | R/W/ E_P | [161] | 0x00 |
| Partitioning Support | PARTITIONING_SUPPORT | 1 | R | [160] | 0x07 |

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| | | | | | | | |
|----------------------------------------------------------|------------------------------------|----|-------------------|-----------|-------|-------|-------|
| Max Enhanced Area Size | MAX_ENH_SIZE_MULT | 3 | R | [159:157] | 0x1D2 | 0x3A4 | 0x748 |
| Partitions attribute | PARTITIONS_ATTRIBUTE | 1 | R/W | [156] | 0x00 | | |
| Partitioning Setting | PARTITION_SETTING_COMPLETED | 1 | R/W | [155] | 0x00 | | |
| General Purpose Partition Size | GP_SIZE_MULT | 12 | R/W | [154:143] | 0x00 | | |
| Enhanced User Data Area Size | ENH_SIZE_MULT | 3 | R/W | [142:140] | 0x00 | | |
| Enhanced User Data Start Address | ENH_START_ADDR | 4 | R/W | [139:136] | 0x00 | | |
| Reserved | | 1 | - | [135] | - | | |
| Bad Block Management mode | SEC_BAD_BLK_MGMNT | 1 | R/W | [134] | 0x00 | | |
| Production state awareness | PRODUCTION_STATE_AWARENESS | 1 | R/W/E | [133] | 0x00 | | |
| Package Case Temperature is controlled | TCASE_SUPPORT | 1 | W/E_P | [132] | 0x00 | | |
| Periodic Wake-up | PERIODIC_WAKEUP | 1 | R/W/E | [131] | 0x00 | | |
| Program CID/CSD in DDR mode support | PROGRAM_CID_CSD_DDR_SUPPORT | 1 | R | [130] | 0x01 | | |
| Reserved | | 2 | - | [129:128] | - | | |
| Vendor Specific Fields | VENDOR_SPECIFIC_FIELD | 64 | <vendor specific> | [127:64] | - | | |
| Native sector size | NATIVE_SECTOR_SIZE | 1 | R | [63] | 0x00 | | |
| Sector size emulation | USE_NATIVE_SECTOR | 1 | R/W | [62] | 0x00 | | |
| Sector size | DATA_SECTOR_SIZE | 1 | R | [61] | 0x00 | | |
| 1st initialization after disabling sector size emulation | INI_TIMEOUT_EMU | 1 | R | [60] | 0x00 | | |
| Class 6 commands control | CLASS_6_CTRL | 1 | R/W/E_P | [59] | 0x00 | | |
| Number of addressed group to be Released | DYNCAP_NEEDED | 1 | R | [58] | 0x00 | | |
| Exception events control | EXCEPTION_EVENTS_CTRL | 2 | R/W/E_P | [57:56] | 0x00 | | |
| Exception events status | EXCEPTION_EVENTS_STATUS | 2 | R | [55:54] | 0x00 | | |
| Extended Partitions Attribute | EXT_PARTITIONS_ATTRIBUTE | 2 | R/W | [53:52] | 0x00 | | |
| Context configuration | CONTEXT_CONF | 15 | R/W/E_P | [51:37] | 0x00 | | |
| Packed command status | PACKED_COMMAND_STATUS | 1 | R | [36] | 0x00 | | |
| Packed command failure index | PACKED_FAILURE_INDEX | 1 | R | [35] | 0x00 | | |
| Power Off Notification | POWER_OFF_NOTIFICATION | 1 | R/W/E_P | [34] | 0x00 | | |
| Control to turn the Cache ON/OFF | CACHE_CTRL | 1 | R/W/E_P | [33] | 0x00 | | |
| Flushing of the cache | FLUSH_CACHE | 1 | W/E_P | [32] | 0x00 | | |
| Control to turn the Barrier ON/OFF | BARRIER_CTRL | 1 | R | [31] | 0x00 | | |
| Mode config | MODE_CONFIG | 1 | R/W/E_P | [30] | 0x00 | | |
| Mode operation codes | MODE_OPERATION_CODES | 1 | W/E_P | [29] | 0x00 | | |
| Reserved | | 2 | - | [28:27] | - | | |
| FFU status | FFU_STATUS | 1 | R | [26] | 0x00 | | |
| Pre loading data size | PRE_LOADING_DATA_SIZE | 4 | R/W/E_P | [25:22] | 0x00 | | |
| Max pre loading data size | MAX_PRE_LOADING_DATA_SIZE | 4 | R | [21:18] | 0x00 | | |
| Product state awareness enablement | PRODUCT_STATE_AWARENESS_ENABLEMENT | 1 | R/W/E&R | [17] | 0x00 | | |
| Secure Removal Type | SECURE_REMOVAL_TYPE | 1 | R/W&R | [16] | 0x39 | | |
| Command Queue Mode Enable | CMDQ_MODE_EN | 1 | R/W/E_P | [15] | 0x00 | | |
| Reserved | | 15 | - | [14:0] | - | | |

NOTE :

1) Reserved bits should read as "0."

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8.0 AC PARAMETER

8.1 Timing Parameter

[Table 25] Timing Parameter

| Timing Paramter | Max. Value | Unit |
|------------------------------------------|------------|------|
| Read Timeout | 100 | ms |
| Write Timeout | 350 | ms |
| Erase Timeout | 20 | ms |
| Force Erase Timeout | 3 | min |
| Secure Erase Timeout | 8 | s |
| Secure Trim step1 Timeout | 5 | s |
| Secure Trim step2 Timeout | 3 | s |
| Trim Timeout | 600 | ms |
| Partition Switching Timeout (after Init) | 1 | ms |
| Power Off Notification (Short) Timeout | 20 | ms |
| Power Off Notification (Long) Timeout | 600 | ms |
| Sleep Mode ³⁾ | 0.1 | ms |

NOTE :
 Be advised Timeout Values specified in the table above are for testing purposes under Samsung test pattern only. EXCEPTION_EVENT may occur and the actual timeout situation may vary due to user environment.

1) Normal initialization time without initial partition setting.

2) Initialization Time after partition setting, refer to INI_TIMEOUT_AP in 6.4 EXT_CSD register.

This Initialization Time for partition setting operates once in the first place during lifetime.

3) To access sleep mode, host should issue CMD5. It takes less than 0.1 ms to go to sleep mode in device after issuing CMD5. NAND will be off during sleep mode.

8.2 Previous Bus Timing Parameters for DDR52 and HS200 Mode are defined by JEDEC Standard

8.3 Bus Timing Specification in HS400 Mode

8.3.1 HS400 Device Input Timing

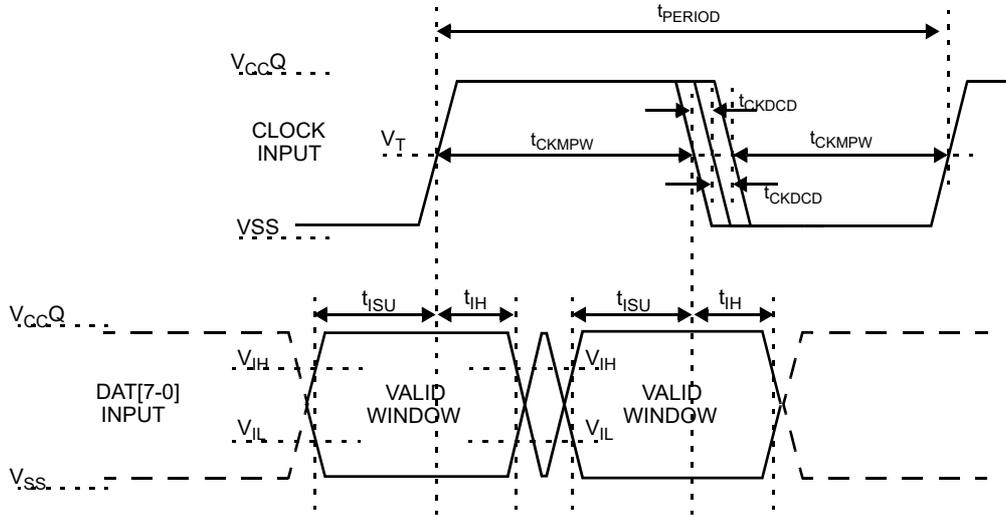


Figure 6. HS400 Device Input Timing

NOTE :

- 1) t_{ISU} and t_{IH} are measured at $V_{IL}(\text{max.})$ and $V_{IH}(\text{min.})$.
- 2) V_{IH} denotes $V_{IH}(\text{min.})$ and V_{IL} denotes $V_{IL}(\text{max.})$.

[Table 26] HS400 Device Input Timing

| Parameter | Symbol | Min | Max | Unit |
|-------------------------------|--------------|-------|-----|------|
| Input CLK | | | | |
| Cycle time data transfer mode | t_{PERIOD} | 5 | - | ns |
| Slew rate | SR | 1.125 | - | V/ns |
| Duty cycle distortion | t_{CKDCD} | 0.0 | 0.3 | ns |
| Minimum pulse width | t_{CKMPW} | 2.2 | - | ns |
| Input DAT (referenced to CLK) | | | | |
| Input set-up time | t_{ISUddr} | 0.4 | - | ns |
| Input hold time | t_{IHddr} | 0.4 | - | ns |
| Slew rate | SR | 1.125 | - | V/ns |

8.3.2 HS400 Device Output Timing

Data Strobe is used to read data(data read and CRC status response read) in HS400 mode. The device output value of Data Strobe is “High-Z” when the device is not in outputting data(data read, CRC status response). Data Strobe is toggled only during data read period.

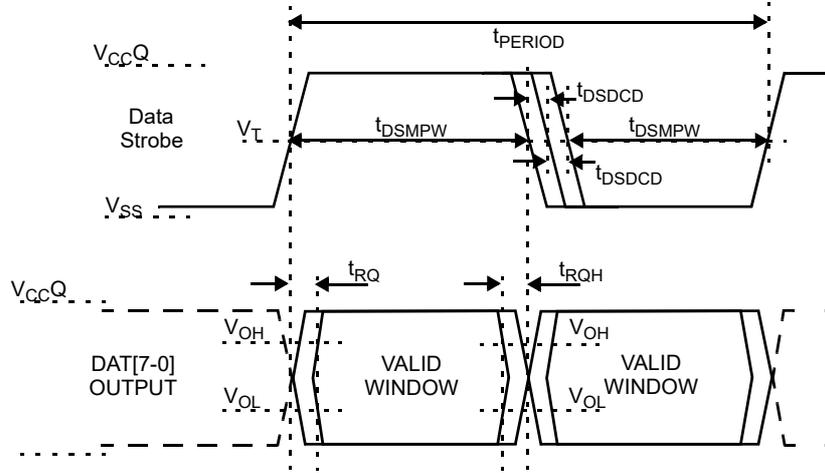


Figure 7. HS400 Device Output Timing

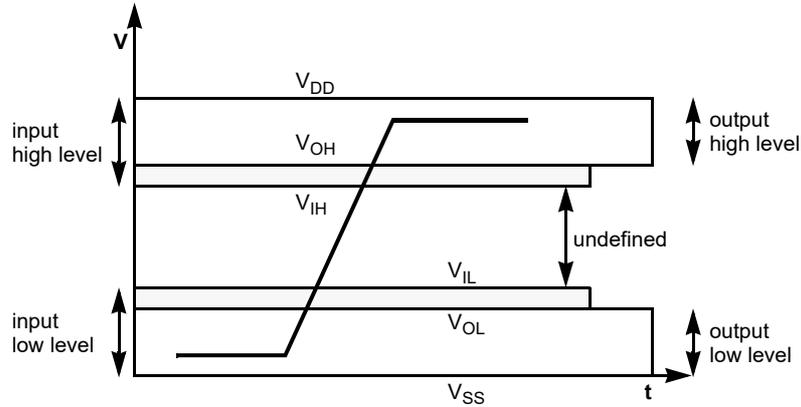
NOTE :
 V_{OH} denotes V_{OH}(min.) and V_{OL} denotes V_{OL}(max.).

[Table 27] HS400 Device Output Timing

| Parameter | Symbol | Min | Max | Unit |
|----------------------------------------|---------------------|-------|-----|---------------------|
| Data Strobe | | | | |
| Cycle time data transfer mode | t _{PERIOD} | 5 | - | ns |
| Slew rate | SR | 1.125 | - | V/ns |
| Duty cycle distortion | t _{DSDCD} | 0.0 | 0.2 | ns |
| Minimum pulse width | t _{DSMPW} | 2.0 | - | ns |
| Read pre-amble | t _{RPRE} | 0.4 | - | t _{PERIOD} |
| Read post-amble | t _{RPST} | 0.4 | - | t _{PERIOD} |
| Output DAT (referenced to Data Strobe) | | | | |
| Output skew | t _{RQ} | - | 0.4 | ns |
| Output hold skew | t _{RQH} | - | 0.4 | ns |
| Slew rate | SR | 1.125 | - | V/ns |

8.4 Bus signal levels

As the bus can be supplied with a variable supply voltage, all signal levels are related to the supply voltage.



8.4.1 Open-drain Mode Bus Signal Level

[Table 28] Open-drain Bus Signal Level

| Parameter | Symbol | Min | Max. | Unit | Conditions |
|---------------------|----------|----------------|------|------|-------------------------|
| Output HIGH voltage | V_{OH} | $V_{DD} - 0.2$ | - | V | 1) |
| Output LOW voltage | V_{OL} | - | 0.3 | V | $I_{OL} = 2 \text{ mA}$ |

NOTE :

1) Because V_{oh} depends on external resistance value (including outside the package), this value does not apply as device specification. Host is responsible to choose the external pull-up and open drain resistance value to meet V_{oh} Min value.

8.4.2 Push-pull Mode Bus Signal Level eMMC

The device input and output voltages shall be within the following specified ranges for any V_{DD} of the allowed voltage range.

[Table 29] Push-pull Signal Level—High-Voltage eMMC

| Parameter | Symbol | Min | Max. | Unit | Conditions |
|---------------------|----------|-----------------------|-----------------------|------|------------------------------------------------|
| Output HIGH voltage | V_{OH} | $0.75 \cdot V_{CCQ}$ | - | V | $I_{OH} = -100 \text{ uA}@V_{CCQ} \text{ min}$ |
| Output LOW voltage | V_{OL} | - | $0.125 \cdot V_{CCQ}$ | V | $I_{OL} = 100 \text{ uA}@V_{CCQ} \text{ min}$ |
| Input HIGH voltage | V_{IH} | $0.625 \cdot V_{CCQ}$ | $V_{CCQ} + 0.3$ | V | - |
| Input LOW voltage | V_{IL} | $V_{SS} - 0.3$ | $0.25 \cdot V_{CCQ}$ | V | - |

[Table 30] Push-pull Signal Level—1.70 - 1.95 V_{CCQ} Voltage Range

| Parameter | Symbol | Min | Max. | Unit | Conditions |
|---------------------|----------|---------------------------|---------------------------|------|-----------------|
| Output HIGH voltage | V_{OH} | $V_{CCQ} - 0.45V$ | - | V | $I_{OH} = -2mA$ |
| Output LOW voltage | V_{OL} | - | 0.45V | V | $I_{OL} = 2mA$ |
| Input HIGH voltage | V_{IH} | $0.65 \cdot V_{CCQ}^{1)}$ | $V_{CCQ} + 0.3$ | V | - |
| Input LOW voltage | V_{IL} | $V_{SS} - 0.3$ | $0.35 \cdot V_{CCQ}^{2)}$ | V | - |

NOTE :

1) $0.7 \cdot V_{CCQ}$ for MMC4.3 and older revisions.

2) $0.3 \cdot V_{CCQ}$ for MMC4.3 and older revisions.

IF THERE IS ANY OTHER OPERATION TO IMPLEMENT IN ADDITION TO SPECIFICATION IN THE DATASHEET OR JEDEC STANDARD, PLEASE CONTACT EACH BRANCH OFFICE OR HEADQUARTERS OF SAMSUNG ELECTRONICS.

9.0 DC PARAMETER

9.1 Patrol Read Mode

9.1.1 Active Power Consumption during Operation

[Table 31] Active Power Consumption during Operation

| Density | NAND Type | CTRL | NAND | Unit |
|---------|--------------|------|------|------|
| 8 GB | 64 Gb MLC x1 | 180 | 50 | mA |
| 16 GB | 64 Gb MLC x2 | 180 | 100 | |
| 32 GB | 64 Gb MLC x4 | 180 | 200 | |

* Power Measurement conditions: Bus configuration =x8 @200MHz DDR

* The measurement for max RMS current is the average RMS current consumption over a period of 100ms.

9.1.2 Standby Power Consumption in Standby State

[Table 32] Standby Power Consumption in Standby State (Patrol Read Activate)

| Density | NAND Type | CTRL | | NAND | | Unit |
|---------|--------------|-----------|------------|-----------|------------|------|
| | | 25°C(Typ) | 105°C(Typ) | 25°C(Typ) | 105°C(Typ) | |
| 8 GB | 64 Gb MLC x1 | 180 | | 50 | | mA |
| 16 GB | 64 Gb MLC x2 | 180 | | 100 | | |
| 32 GB | 64 Gb MLC x4 | 180 | | 200 | | |

NOTE :

Power Measurement conditions: Bus configuration =x8, No CLK

*Typical value is measured at V_{CC}=3.3V, T_C=25°C. Not 100% tested.

[Table 33] Standby Power Consumption in Standby State (Patrol Read Inactivate)

| Density | NAND Type | CTRL | | Unit | NAND | | Unit |
|---------|--------------|-----------|------------|------|-----------|------------|------|
| | | 25°C(Typ) | 105°C(Typ) | | 25°C(Typ) | 105°C(Typ) | |
| 8 GB | 64 Gb MLC x1 | 120 | | uA | 85 | | uA |
| 16 GB | 64 Gb MLC x2 | 120 | | | 135 | | |
| 32 GB | 64 Gb MLC x4 | 120 | | | 235 | | |

NOTE : Power Measurement conditions: Bus configuration =x8, No CLK

*Typical value is measured at V_{CC}=3.3V, T_C=25°C. Not 100% tested.

9.1.3 Sleep Power Consumption in Sleep State

[Table 34] Sleep Power Consumption in Sleep State

| Density | NAND Type | CTRL | | NAND | | Unit |
|---------|--------------|-----------|------------|-----------------|------------|------|
| | | 25°C(Typ) | 105°C(Typ) | 25°C(Typ) | 105°C(Typ) | |
| 8 GB | 64 Gb MLC x1 | 400 | 1000 | 0 ¹⁾ | | uA |
| 16 GB | 64 Gb MLC x2 | 400 | 1000 | 0 ¹⁾ | | |
| 32 GB | 64 Gb MLC x4 | 400 | 1000 | 0 ¹⁾ | | |

NOTE : 1) In sleep mode NAND power can be turned off.

If NAND power is alive, NAND power is same with that of the Standby state.

9.2 Supply Voltage

[Table 35] Supply Voltage

| Item | Min | Max | Unit |
|-------------------------------------|------------|------------|------|
| V _{DD} (V _{CCQ}) | 1.70 (2.7) | 1.95 (3.6) | V |
| V _{DDF} (V _{CC}) | 2.7 | 3.6 | V |
| V _{SS} | -0.5 | 0.5 | V |

9.3 Bus Signal Line Load

The total capacitance C_L of each line of the eMMC bus is the sum of the bus master capacitance C_{HOST}, the bus capacitance C_{BUS} itself and the capacitance C_{DEVICE} of the eMMC connected to this line:

$$C_L = C_{HOST} + C_{BUS} + C_{DEVICE}$$

The sum of the host and bus capacitances should be under 20pF.

[Table 36] Bus Signal Line Load

| Parameter | Symbol | Min | Typ. | Max | Unit | Remark |
|---------------------------------------|---------------------|-----|------|-----|------|---------------------------------------|
| Pull-up resistance for CMD | R _{CMD} | 4.7 | - | 100 | KOhm | to prevent bus floating |
| Pull-up resistance for DAT0-DAT7 | R _{DAT} | 10 | - | 100 | KOhm | to prevent bus floating |
| Internal pull up resistance DAT1-DAT7 | R _{int} | 10 | - | 150 | KOhm | to prevent unconnected lines floating |
| Single Device capacitance | C _{DEVICE} | - | - | 12 | pF | - |
| Maximum signal line inductance | | - | - | 16 | nH | f _{PP} <= 52 MHz |

[Table 37] Capacitance and Resistance for HS400 mode

| Parameter | Symbol | Min | Typ | Max | Unit | Remark |
|--------------------------------------|--------------------------|-----|-----|-----|------|---------------|
| Bus signal line capacitance | CL | - | - | 13 | pF | Single Device |
| Single Device capacitance | C _{DEVICE} | - | - | 6 | pF | - |
| Pull-down resistance for Data Strobe | R _{Data Strobe} | 10 | - | 100 | KOhm | - |